

Application/Control No.	Applicant(s)/Patent under Reexamination
10/560,051	OKABE ET AL.
Examiner	Art Unit
Son T. Nauven	3643

	SEARCHED				
Class	Subclass	Date	Examiner		
47	60 61	3/25/2009	STN		
	17 19.2				
	19.1				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
IPC foreign search and text search, see printouts	3/25/2009	STN